

PCN Number:	20210112004.2			PCN Date:	Feb 5 2021				
Title:	Qualification of Cu as an alternate bond wire for select devices								
Customer Contact:	PCN Manager	Dept:	Quality Services						
Proposed 1st Ship Date:	Aug 4 2021	Estimated Sample Availability:	Date provided at sample request						
Change Type:									
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Site				
<input checked="" type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Material				
<input checked="" type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input type="checkbox"/>	Wafer Bump Process				
<input type="checkbox"/>	Mechanical Specification	<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Wafer Fab Site				
<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input type="checkbox"/>	Wafer Fab Materials				
		<input type="checkbox"/>		<input type="checkbox"/>	Wafer Fab Process				
PCN Details									
Description of Change:									
<p>This PCN is to inform of an alternative bond wire qualification for the devices in the product affected section as follows:</p> <table border="1" style="margin-left: auto; margin-right: auto;"> <thead> <tr> <th style="text-align: center;">Current Bond wire, Diameter</th> <th style="text-align: center;">Additional Bond wire, diameter</th> </tr> </thead> <tbody> <tr> <td style="text-align: center;">Au, 1.0 mils</td> <td style="text-align: center;">Cu, 0.8 mils</td> </tr> </tbody> </table>						Current Bond wire, Diameter	Additional Bond wire, diameter	Au, 1.0 mils	Cu, 0.8 mils
Current Bond wire, Diameter	Additional Bond wire, diameter								
Au, 1.0 mils	Cu, 0.8 mils								
Reason for Change:									
<p>Continuity of supply.</p> <ol style="list-style-type: none"> 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties 2) Maximize flexibility within our Assembly/Test production sites. 3) Cu is easier to obtain and stock 									
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):									
None									
Anticipated impact on Material Declaration									
<input type="checkbox"/>	No Impact to the Material Declaration	<input checked="" type="checkbox"/>	Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained at the site link below http://www.ti.com/quality/docs/materialcontentsearch.tsp						
Changes to product identification resulting from this PCN:									
None									
Product Affected:									
DS90UA101TRTVJQ1	DS90UB914ATRHSJQ1	DS90UH302QSQX/NOPB	DS90UR905QSQE/E7002382						
DS90UA101TRTVRQ1	DS90UB914ATRHSRQ1	DS90UH925QSQ/E7002397	DS90UR905QSQE/NOPB						
DS90UA101TRTVTQ1	DS90UB914ATRSTQ1	DS90UH925QSQ/NOPB	DS90UR905QSQX/E7002382						
DS90UA102TRHSJQ1	DS90UB914QSQ/NOPB	DS90UH925QSQE/E7002397	DS90UR905QSQX/E7002600						
DS90UA102TRHSRQ1	DS90UB914QSQE/NOPB	DS90UH925QSQE/NOPB	DS90UR905QSQX/NOPB						
DS90UA102TRHSTQ1	DS90UB914QSQX/NOPB	DS90UH925QSQX/E7002397	DS90UR906QSQ/E7002383						

DS90UB301ATRHSRQ1	DS90UB921TRHSRQ1	DS90UH925QSX/NOPB	DS90UR906QSQ/NOPB
DS90UB301ATRSTQ1	DS90UB921TRHSTQ1	DS90UH926QSQ/E7002384	DS90UR906QSQE/E7002383
DS90UB301QSQ/NOPB	DS90UB925QSQ/E7002826	DS90UH926QSQ/NOPB	DS90UR906QSQE/NOPB
DS90UB301QSQE/NOPB	DS90UB925QSQ/NOPB	DS90UH926QSQ/S7002920	DS90UR906QSX/E7002383
DS90UB302QSQ/NOPB	DS90UB925QSQE/E7002826	DS90UH926QSQE/E7002384	DS90UR906QSX/NOPB
DS90UB302QSQE/NOPB	DS90UB925QSQE/NOPB	DS90UH926QSQE/J7003048	DS90UR907QSQ/E7003100
DS90UB302QSX/NOPB	DS90UB925QSX/E7002826	DS90UH926QSQE/NOPB	DS90UR907QSQ/NOPB
DS90UB303TRTARQ1	DS90UB925QSX/NOPB	DS90UH926QSX/E7002384	DS90UR907QSQE/E7003100
DS90UB303TRTATQ1	DS90UB926QSQ/E7002827	DS90UH926QSX/J7003049	DS90UR907QSQE/NOPB
DS90UB633ARTVRQ1	DS90UB926QSQ/NOPB	DS90UH926QSX/NOPB	DS90UR907QSX/E7003100
DS90UB633ARTVTQ1	DS90UB926QSQE/E7002827	DS90UH927QSQ/E7002392	DS90UR907QSX/NOPB
DS90UB901QSQ/NOPB	DS90UB926QSQE/NOPB	DS90UH927QSQ/NOPB	DS90UR908QSQ/NOPB
DS90UB901QSQE/NOPB	DS90UB926QSX/E7002827	DS90UH927QSQE/E7002392	DS90UR908QSQE/NOPB
DS90UB901QSX/NOPB	DS90UB926QSX/E7002956	DS90UH927QSQE/NOPB	DS90UR908QSX/NOPB
DS90UB902QSQ/NOPB	DS90UB926QSX/NOPB	DS90UH927QSX/E7002392	DS90UR910QSQ/NOPB
DS90UB902QSQE/NOPB	DS90UB927QSQ/NOPB	DS90UH927QSX/NOPB	DS90UR910QSQE/E7002687
DS90UB902QSX/NOPB	DS90UB927QSQE/E7003111	DS90UH940NTNKDRQ1	DS90UR910QSQE/NOPB
DS90UB903QSQ/NOPB	DS90UB927QSQE/NOPB	DS90UH940NTNKDTQ1	DS90UR910QSX/NOPB
DS90UB903QSQE/NOPB	DS90UB927QSX/NOPB	DS90UH940TNKDRQ1	DS90UR916QSQ/E7002619
DS90UB903QSX/NOPB	DS90UB933TRTVRQ1	DS90UH940TNKDTQ1	DS90UR916QSQ/NOPB
DS90UB903QSX/S7002782	DS90UB933TRTVTQ1	DS90UH948TNKDRQ1	DS90UR916QSQE/E7002619
DS90UB904QSQ/NOPB	DS90UB940NTNKDRQ1	DS90UH948TNKDTQ1	DS90UR916QSQE/NOPB
DS90UB904QSQE/J7003047	DS90UB940NTNKDTQ1	DS90UR903QSQ/NOPB	DS90UR916QSX/E7002619
DS90UB904QSQE/NOPB	DS90UB940TNKDRQ1	DS90UR903QSQE/NOPB	DS90UR916QSX/NOPB
DS90UB904QSX/NOPB	DS90UB940TNKDTQ1	DS90UR903QSX/NOPB	DS99R124AQSQ/NOPB
DS90UB904QSX/S7002783	DS90UB948TNKDRQ1	DS90UR904QSQ/NOPB	DS99R124AQSQE/NOPB
DS90UB913ATRJVQ1	DS90UB948TNKDTQ1	DS90UR904QSQE/J7003050	DS99R124AQSX/NOPB
DS90UB913ATRTRV/S2	DS90UH301QSQ/NOPB	DS90UR904QSQE/NOPB	DS99R124QSQ/E7002678
DS90UB913ATRTRVQ1	DS90UH301QSQE/NOPB	DS90UR904QSX/J7003069	DS99R124QSQ/NOPB
DS90UB913ATRVTQ1	DS90UH301QSX/NOPB	DS90UR904QSX/NOPB	DS99R124QSQE/NOPB
DS90UB913QSQ/NOPB	DS90UH302QSQ/NOPB	DS90UR905QSQ/E7002382	DS99R124QSX/NOPB
DS90UB913QSQE/NOPB	DS90UH302QSQE/NOPB	DS90UR905QSQ/NOPB	PDS90UB923TRTATQ1
DS90UB913QSX/NOPB			

Automotive New Product Qualification Summary (As per AEC-Q100 and JEDEC Guidelines)

Product Attributes

Attributes	Qual Device: DS90UB925QB0RC	Qual Device: DS90UB940RQ	Qual Device: DS99R124AQNR83
Automotive Grade Level	Grade 2	Grade 2	Grade 2
Operating Temp Range	-40 to +105 C	-40 to +105 C	-40 to +105 C
Product Function	Interface	Interface	Interface
Wafer Fab Supplier	FRBW	MAINEFAB	MAINEFAB
Die Revision	A	B	C
Assembly Site	TIEMA	TIEMA	TIEMA
Package Type	WQFN	WQFN	WQFN
Package Designator	RHS	NKD	RHS
Ball/Lead Count	48	64	48

- OBS: Qual By Similarity
- Qual Device DS99R124AQNR83 is qualified at LEVEL3-260CG
- Qual Device DS90UB925QB0RC is qualified at LEVEL3-260CG
- Qual Device DS90UB940RQ is qualified at LEVEL3-260CG

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS/Lot	Test Name / Condition	Duration	Qual Device: DS90UB925QB0RC	Qual Device: DS90UB940RQ	Qual Device: DS99R124AQNR83
Test Group A – Accelerated Environment Stress Tests									
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	Level 3-260C	No Fails	No Fails	No Fails
HAST	A2	JEDEC JESD22-A110	3	77	Biased HAST, 110C/85%RH	264 Hours	1/77/0	3/231/0	-
TC	A4	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle, -65/150C	500 Cycles	1/77/0	3/231/0	3/231/0
TC-WBP	A4	MIL-STD883 Method 2011	1	60	Bond Pull over Ball Post T/C 500 Cycles	Wires	1/30/0	3/90/0	3/90/0

Type	#	Test Spec	Min Lot Qty	SS/Lot	Test Name / Condition	Duration	Qual Device: DS90UB925QB0RC	Qual Device: DS90UB940RQ	Qual Device: DS99R124AQNR83
PTC	A5	JEDEC JESD22-A105	1	45	Power Temperature Cycle	1000 Cycles	N/A	N/A	N/A
HTSL	A6	JEDEC JESD22-A103	1	45	High Temp Storage Bake 150C	500 Hours	1/45/0	3/135/0	-
Test Group B – Accelerated Lifetime Simulation Tests									
HTOL	B1	JEDEC JESD22-A108	3	77	Life Test, 125C	1000 Hours	N/A	N/A	N/A
ELFR	B2	AEC Q100-008	3	800	Early Life Failure Rate, 150C	24 Hours	N/A	N/A	N/A
Test Group C – Package Assembly Integrity Tests									
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear (Cpk>1.67)	Wires	1/30/0	3/90/0	3/90/0
WBP	C2	MIL-STD883 Method 2011	1	30	Wire Bond Pull (Cpk>1.67)	Wires	1/30/0	3/90/0	3/90/0
SD	C3	JEDEC JESD22-B102	1	15	Surface Mount Solderability >95% Lead Coverage	-	-	-	-
PD	C4	JEDEC JESD22-B100 and B108	3	10	Physical Dimensions (Cpk>1.67)	-	-	-	-
LI	C6	JEDEC JESD22-B105	1	50	Lead Integrity	-	-	-	-
Test Group D – Die Fabrication Reliability Tests									
EM	D1	JESD61	-	-	Electromigration	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
TDD	D2	JESD35	-	-	Time Dependant Dielectric Breakdown	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
HCI	D3	JESD60 & 28	-	-	Hot Injection Carrier	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
NBTI	D4	-	-	-	Negative Bias Temperature Instability	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
SM	D5	-	-	-	Stress Migration	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements

A1 (PC): Preconditioning:

Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40°C to +150°C

Grade 1 (or Q): -40°C to +125°C

Grade 2 (or T): -40°C to +105°C

Grade 3 (or I): -40°C to +85°C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold: HTOL, ED

Room/Hot: THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room: AC/uHAST

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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Location	E-Mail
USA	PCNAmericasContact@list.ti.com
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